

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10658630	LEE ET AL.
	<b>Examiner</b> Goetze, Simon A	<b>Art Unit</b> 2617

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
370	328	2/2/2007	SAG
370	338	2/2/2007	SAG
370	465	2/2/2007	SAG
370	466	2/2/2007	SAG
398	58	2/2/2007	SAG
398	59	2/2/2007	SAG
398	60	2/2/2007	SAG
398	61	2/2/2007	SAG
398	62	2/2/2007	SAG
398	63	2/2/2007	SAG
398	64	2/2/2007	SAG
REVIEW	ABOVE	11/21/2007	SAG

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST image and keyword search (USPAT; US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB).	2/2/2007	SAG
Consulted with Edan Orgad (Class 455), Chau T. Nguyen and Melvin Marcelo (both of 370).	2/2/2007	SAG
Consulted with Rafael Perez-Gutierrez (Class 455).	11/21/2007	SAG

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
SEE	ATTACHED SEARCH HISTORY	11/21/2007	SAG